Special Issue

Perceptual Deep Learning in Image Processing and Computer Vision

Message from the Guest Editors

AI has garnered significant interest among academic researchers and industrial practitioners for its recent technological breakthrough in the form of deep learning architectures. Consequently, research directions of image processing and computer vision are shifting from statistical methods to deep learning neural network algorithms. The goal of this Special Issue is to invite frontier research that tackles important and challenging issues in deep learning for image processing, computer vision and perceptual understanding. Both theoretical studies and practical applications are welcome for submission. Topics for this Special Issue include but are not restricted to the following fields:

- Deep learning algorithms

- Deep learning architectural implementations

- Deep learning applications

Guest Editors

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Deadline for manuscript submissions

closed (28 February 2021)

Sensors

an Open Access Journal by MDPI

Impact Factor 3.5
CiteScore 8.2
Indexed in PubMed

mdpi.com/journal/
sensors

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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